Special Issue

Modern Computer Vision and Pattern Recognition

Message from the Guest Editors

It is our pleasure to present a Special Issue of *Applied Sciences* on "Modern Computer Vision and Pattern Recognition" and to invite concerned authors to submit original articles on related topics. In recent years, thanks to modern artificial intelligence techniques such as deep learning and reinforcement learning, remarkable progress has been made in computer vision and pattern recognition. Many influential approaches have been proposed, and they have effectively addressed pattern recognition and computer vision tasks such as object detection and recognition, face recognition, action localization, and person re-identification. However, the more general application scenarios in industrial, medical, transportation, and social areas bring new challenges, such as training data scarcity, data noise, complex label relations, high dimensionality, and imbalance distribution. These challenges urgently require modern computer vision and pattern recognition approaches to provide better solutions. In this Special Issue, we invite submissions exploring advanced research and emerging applications in the fields of computer vision and pattern recognition.

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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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